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Poster
The Extreme Ultraviolet and X-ray Irradiance Sensors (EXIS) instrument onboard the GOES-R Series satellites is part of its solar-pointed payload. The EXIS instrument contains two full-disk instruments: The EUVS (Extreme Ultraviolet Sensor) and XRS (X-ray Sensor). Of particular interest, the EUVS contains a normal-incidence, interference filtered spectrograph, called EUVS-B. This instrument measures four individual emission lines between 115-141 nm. These emission lines are formed in the chromosphere and transition region. When a large eruptive solar-flare occurs, these emissions exhibit oscillations in response to the energetics of the flare. This poster will illustrate the analysis methodology used to derive these waves, and examine these waves for all Solar Cycle 25 X-class flare events.

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